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	Application No.	Applicant(s)
	10/722,346	TOKUNAGA ET AL.
Notice of Allowability	Examiner	Art Unit
	Vutha Siak	2825
	Vuthe Siek	2825
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT IN of the Office or upon petition by the applicant. See 37 CFR 1.31	S (OR REMAINS) CLOSED i i) or other appropriate comm RIGHTS. This application is	n this application. If not included unication will be mailed in due course. THIS
1. $\boxtimes$ This communication is responsive to <u>communication filed</u>	<u> 5/8/06</u> .	
2. The allowed claim(s) is/are 2-20.		
3. Acknowledgment is made of a claim for foreign priority of	ınder 35 U.S.C. § 119(a)-(d)	or (f).
a) ☐ All b) ☐ Some* c) ☐ None of the:		
1. Certified copies of the priority documents have	ve been received.	
2. Certified copies of the priority documents have	e been received in Application	on No
3. Copies of the certified copies of the priority d	ocuments have been receive	ed in this national stage application from the
International Bureau (PCT Rule 17.2(a)).		
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE noted below. Failure to timely comply will result in ABANDON THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		e a reply complying with the requirements
4. A SUBSTITUTE OATH OR DECLARATION must be subinformal patent application (PTO-152) which gives		
5. CORRECTED DRAWINGS ( as "replacement sheets") mu	ust be submitted.	
(a) ☐ including changes required by the Notice of Draftspe	rson's Patent Drawing Revie	w ( PTO-948) attached
1)  hereto or 2)  to Paper No./Mail Date		•
(b) ☐ including changes required by the attached Examine Paper No./Mail Date	r's Amendment / Comment o	r in the Office action of
Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in	1.84(c)) should be written on the header according to 37 C	the drawings in the front (not the back) of FR 1.121(d).
6. DEPOSIT OF and/or INFORMATION about the dep attached Examiner's comment regarding REQUIREMENT		
	,	
Attachment(s)  1. Notice of References Cited (PTO-892)	5 □ Notice of I	nformal Patent Application (PTO-152)
<u> </u>		· · · · · · · · · · · · · · · · · · ·
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	Paper No.	Summary (PTO-413), ./Mail Date
<ol> <li>Information Disclosure Statements (PTO-1449 or PTO/SB Paper No./Mail Date</li> </ol>	/08), 7. ☐ Examiner's	s Amendment/Comment
<ol> <li>Examiner's Comment Regarding Requirement for Deposit of Biological Material</li> </ol>	8. 🛛 Examiner's	s Statement of Reasons for Allowance
C. Diological Material	9.	VUTHE SIEK PRIMARY EXAMINED

Application/Control Number: 10/722,346

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## **DETAILED ACTION**

1. This office action is in response to application 10/722,346 and response under 37 C.F.R. 1.111 filed on 5/8/2006. Claims 2-20 remain pending in the application.

## **EXAMINER'S STATEMENT AS TO THE REASONS FOR ALLOWANCE**

- 2. A certified translation of the priority document has been filed and recorded in the USPTO in order to perfect the claim of priority. Therefore, Pack reference (US 2004/0133369) does not constitute prior art. The rejection has been withdrawn and claims 2-20 are allowed.
- 3. The following is an examiner's statement of reasons for allowance: as to claim 12, the prior art of record does not teach or fairly suggest a method of inspecting a photomask for a semiconductor integrated circuit formed based on drawing patter data comprising following steps of classifying a drawing pattern of the semiconductor integrated circuit into a plurality of ranks in accordance with a reference depending on a feature of the drawing pattern and extracting the classified drawing pattern; determining inspecting accuracy for each of the ranks; and deciding quality of the photomask depending on whether the determined inspecting accuracy is satisfied for each drawing pattern thus extracted, wherein the deciding step servers to change an accuracy condition depending on an increase or decrease in a pattern width.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Vuthe Siek whose telephone number is (571) 272-1906. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jack Chiang can be reached on (571) 272-7483. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Vuthe Siek

PRIMARY EXAMINER